

[54] INTERGRATED CIRCUIT TESTER

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[73] Assignee: Hilevel Technology, Irvine, Calif.

[\*\*] Term: 14 Years

[21] Appl. No.: 296,185

[22] Filed: Jan. 11, 1989

[52] U.S. Cl. .... D10/75

[58] Field of Search ..... D10/46, 75; D14/102, D14/103, 104; 324/158 F, 158 P; 439/68, 78

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HILEVEL Technology, Inc. advertising brochure for TOPAZ-V.

Primary Examiner—Nelson C. Holtje  
Assistant Examiner—Antoine D. Davis

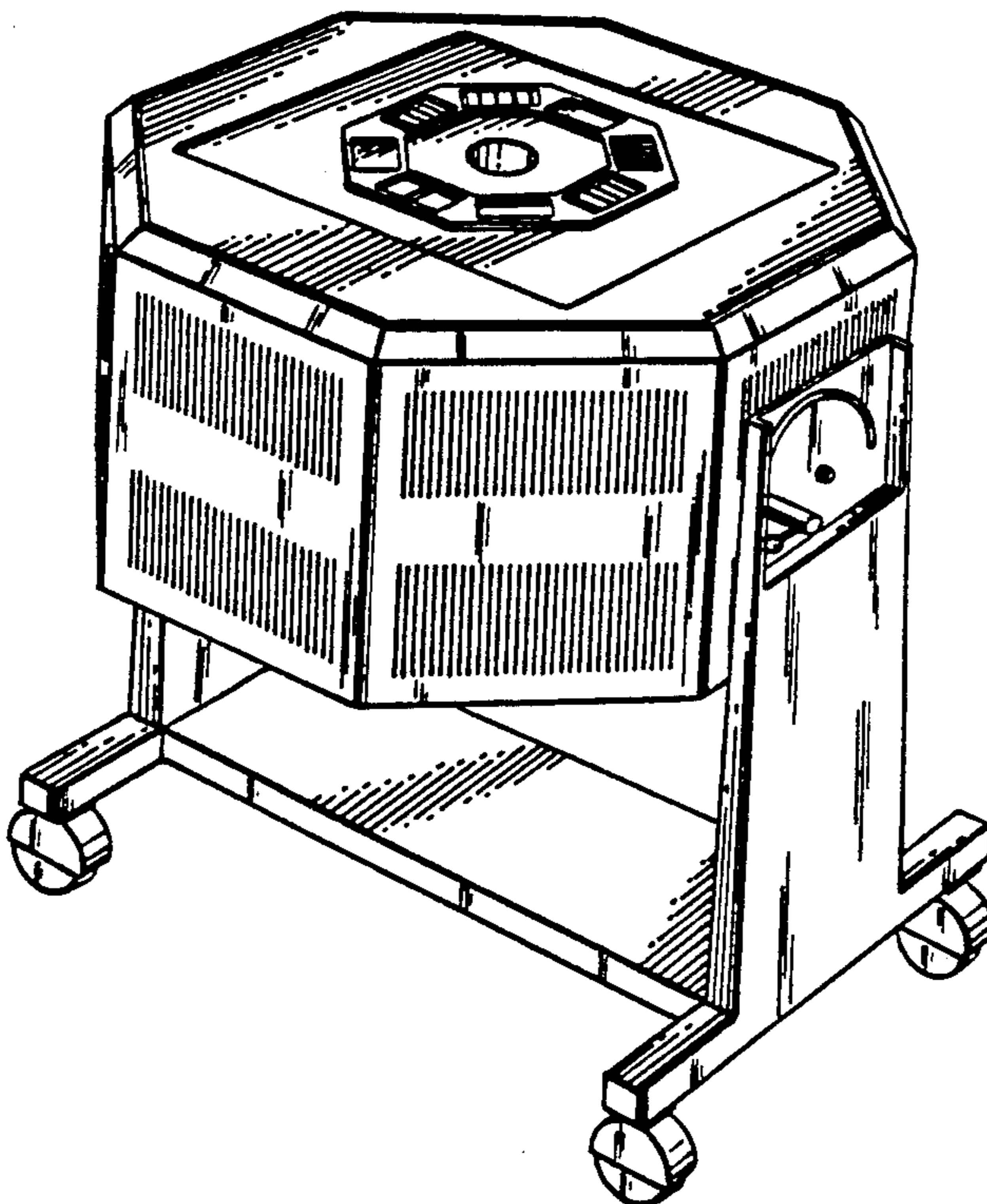
Attorney, Agent, or Firm—Knobbe, Martens, Olson & Bear

[57] CLAIM

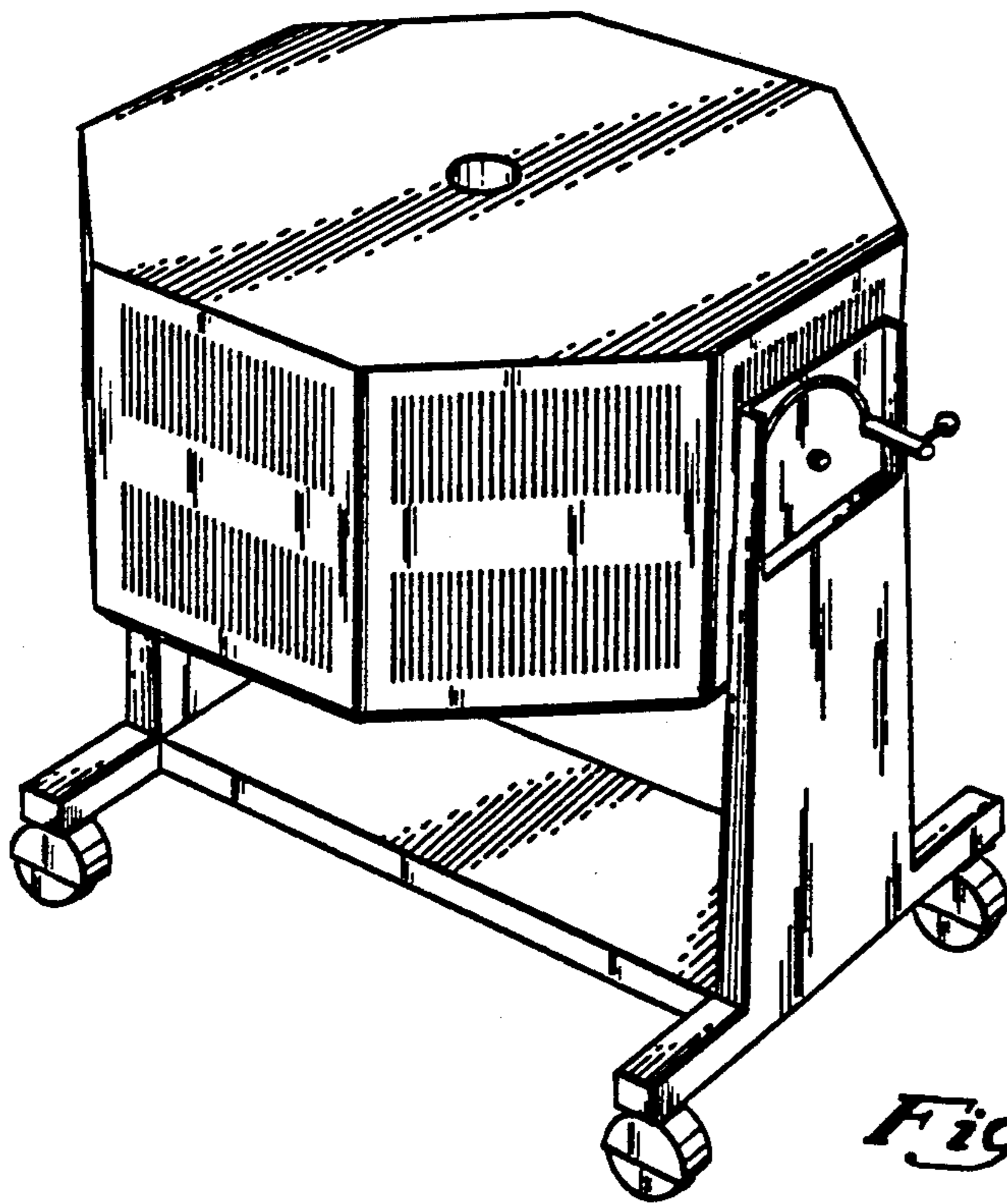
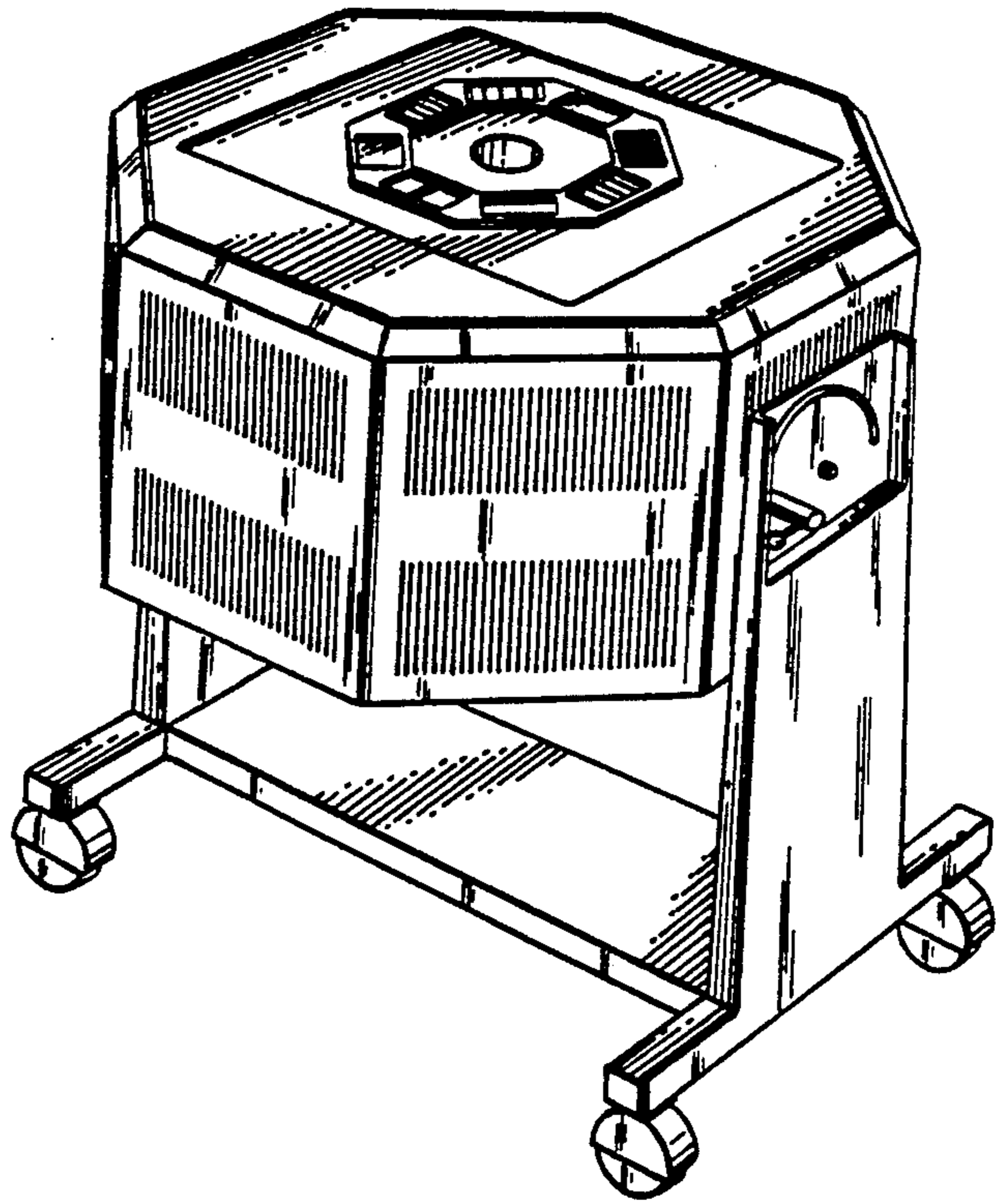
The ornamental design for a intergrated circuit tester, as shown and described.

DESCRIPTION

FIG. 1 is a top, front and right side perspective view of a intergrated circuit tester showing our new design; FIG. 2 is a top, front and right side perspective view, with the circuitry enclosure rotated 180 degrees; FIG. 3 is a top plan view; FIG. 4 is a right side elevational view; FIG. 5 is a front elevational view; FIG. 6 is a rear elevational view; FIG. 7 is a top, front and right side perspective view of a second embodiment of our new design of FIGS. 1-6; FIG. 8 is a top, front and right side perspective view, with the circuitry enclosure rotated 180 degrees; FIG. 9 is a top plan view; FIG. 10 is a right side elevational view, the left side elevational view being a mirror image; FIG. 11 is a front elevational view; FIG. 12 is a rear elevational view; FIG. 13 is a top, front and right side perspective view of a third embodiment of our new design of FIGS. 1-6; FIG. 14 is a top, front and right side perspective view, with the circuitry enclosure rotated 180 degrees; FIG. 15 is a top plan view; FIG. 16 is a right side elevational view, the left side elevational view being a mirror image; FIG. 17 is a front elevational view; and FIG. 18 is a rear elevational view thereof.

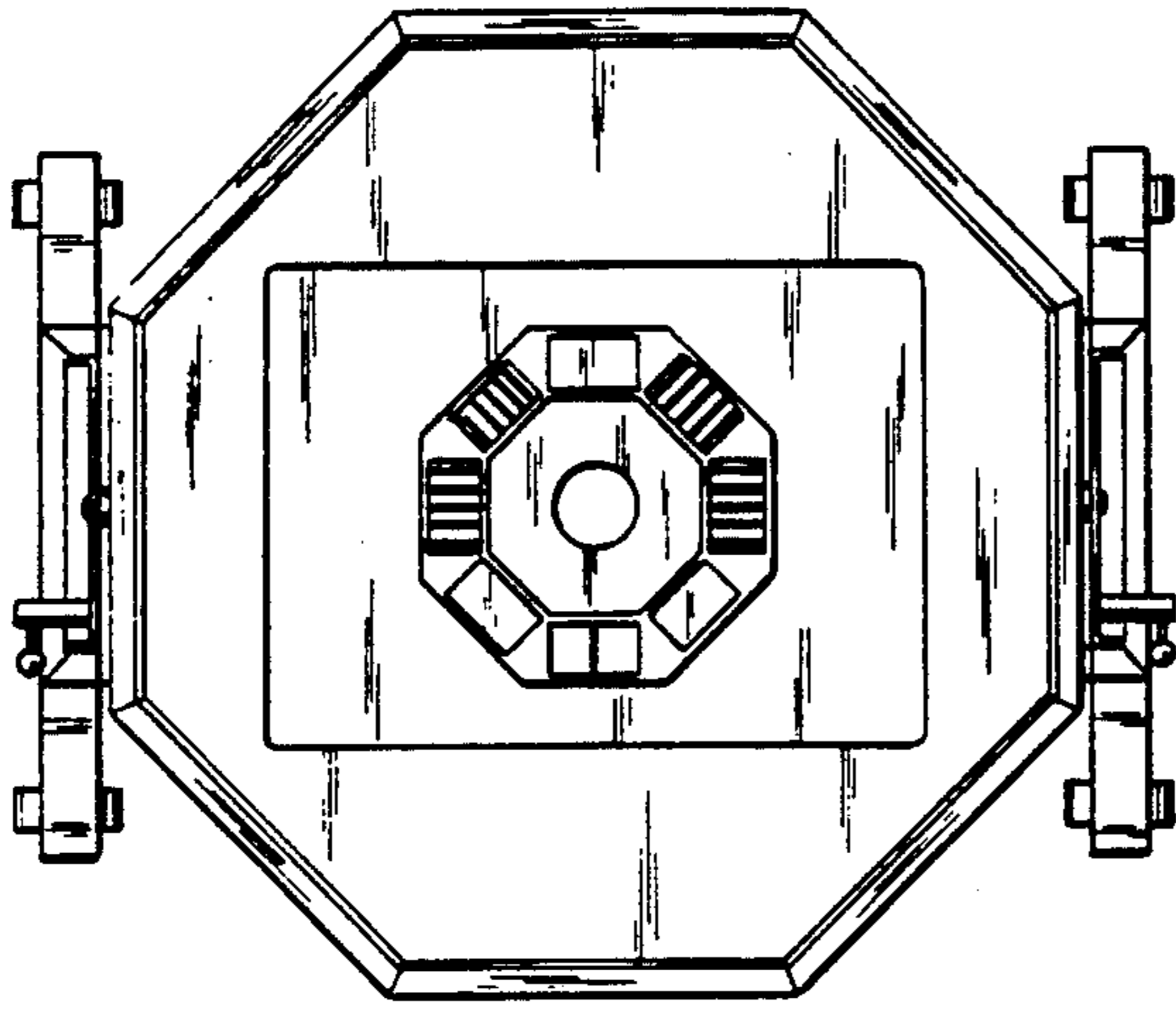


*Fig. 1*

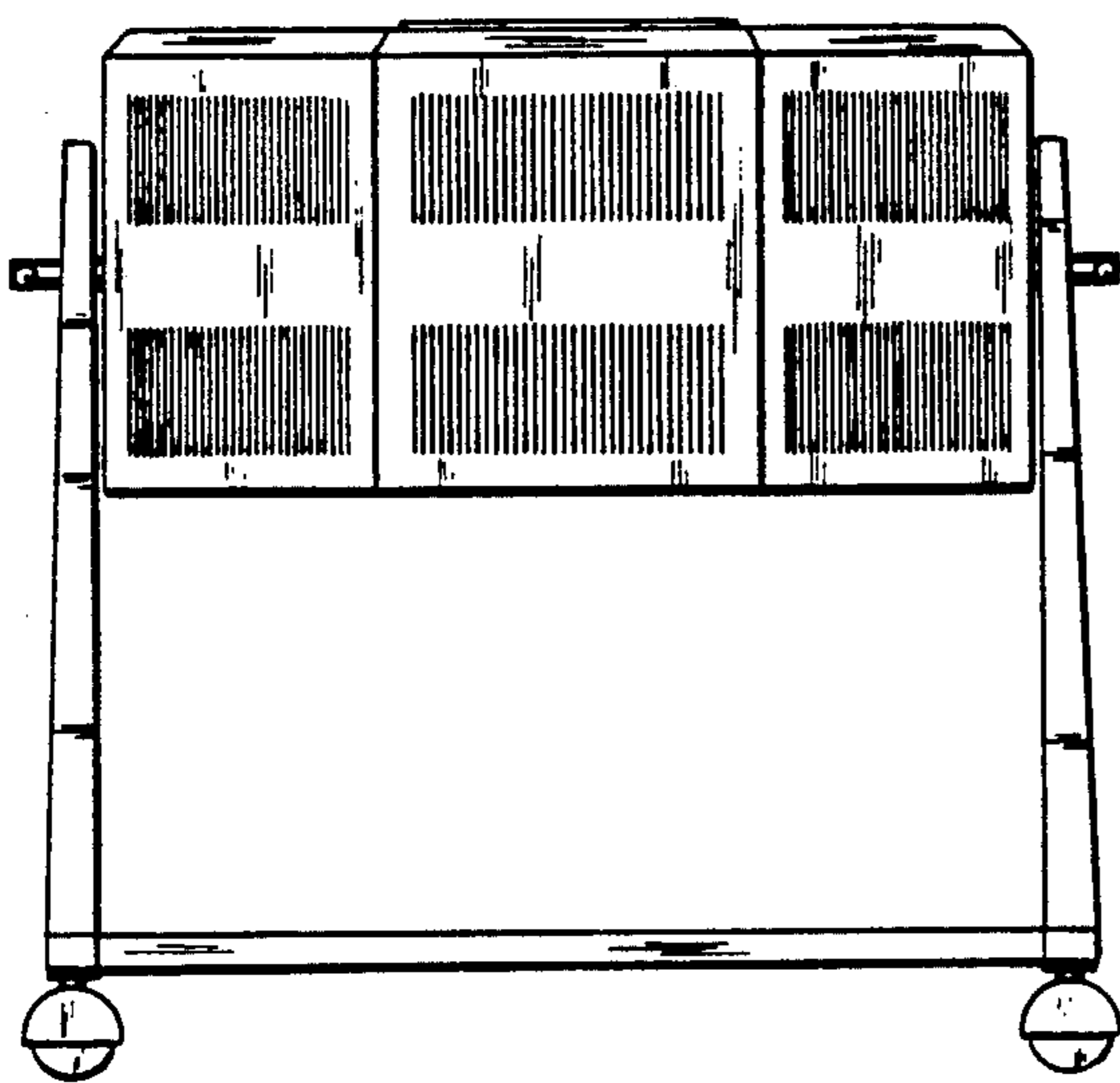
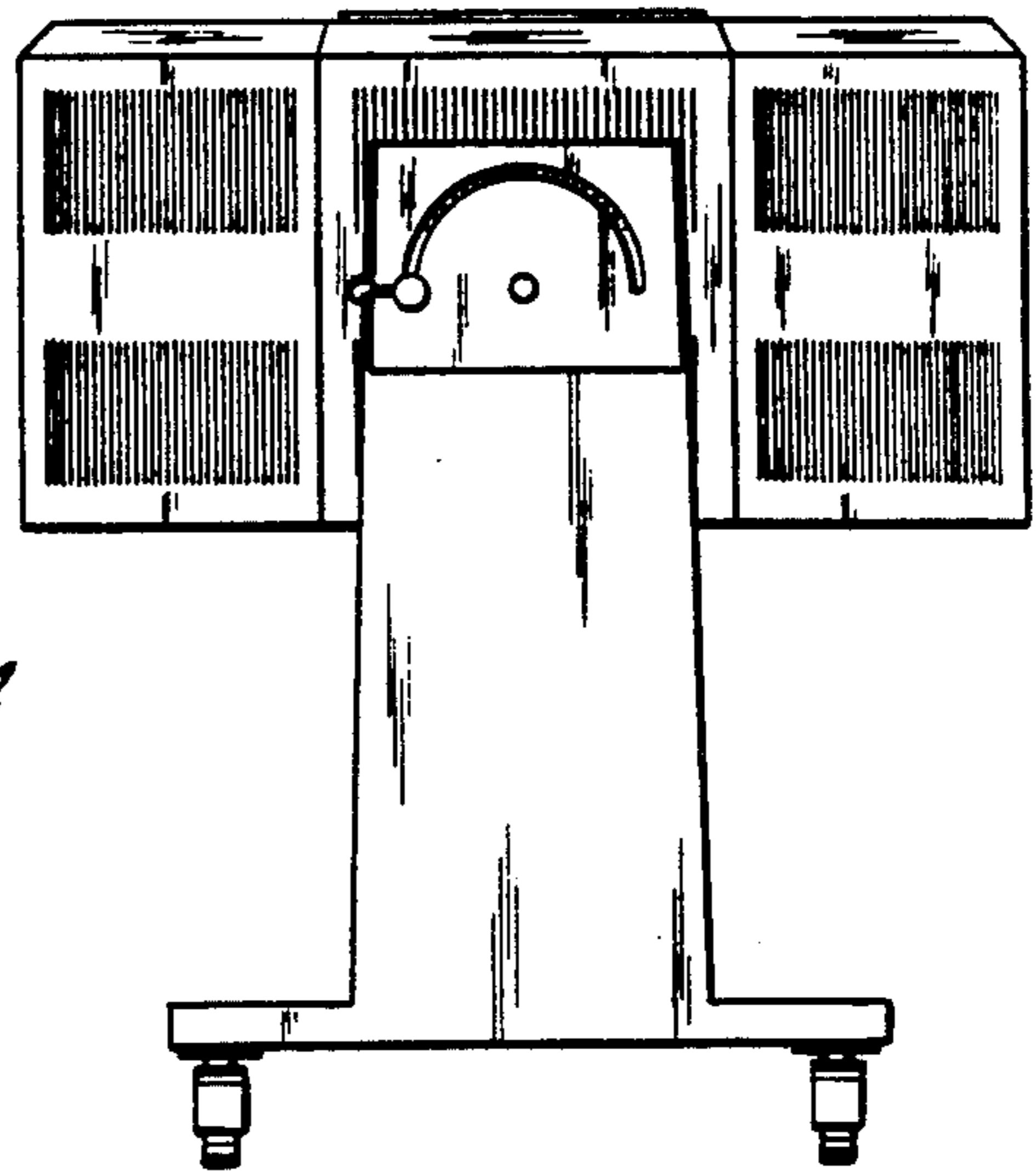


*Fig. 2*

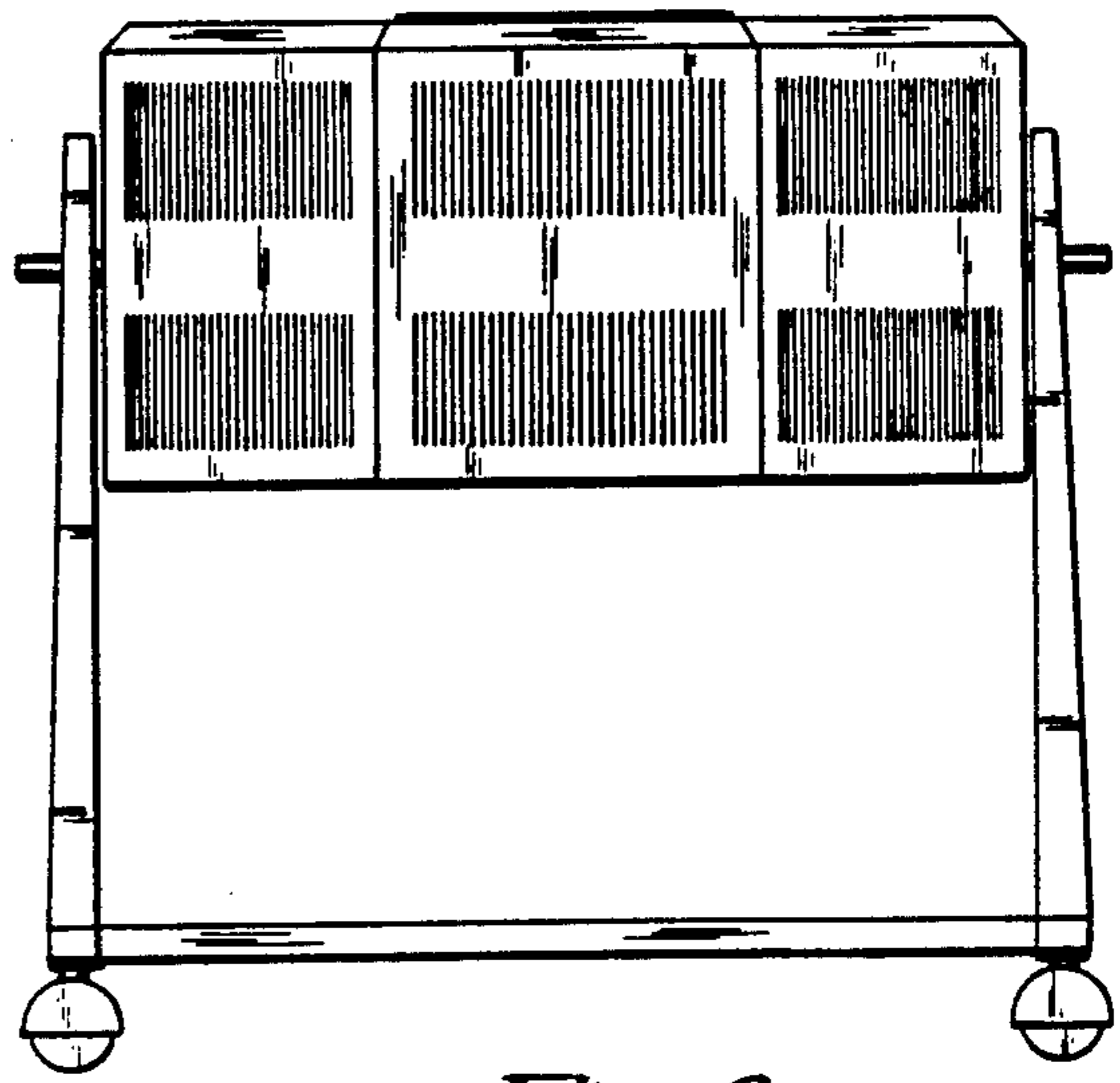
*Fig. 3*



*Fig. 4*

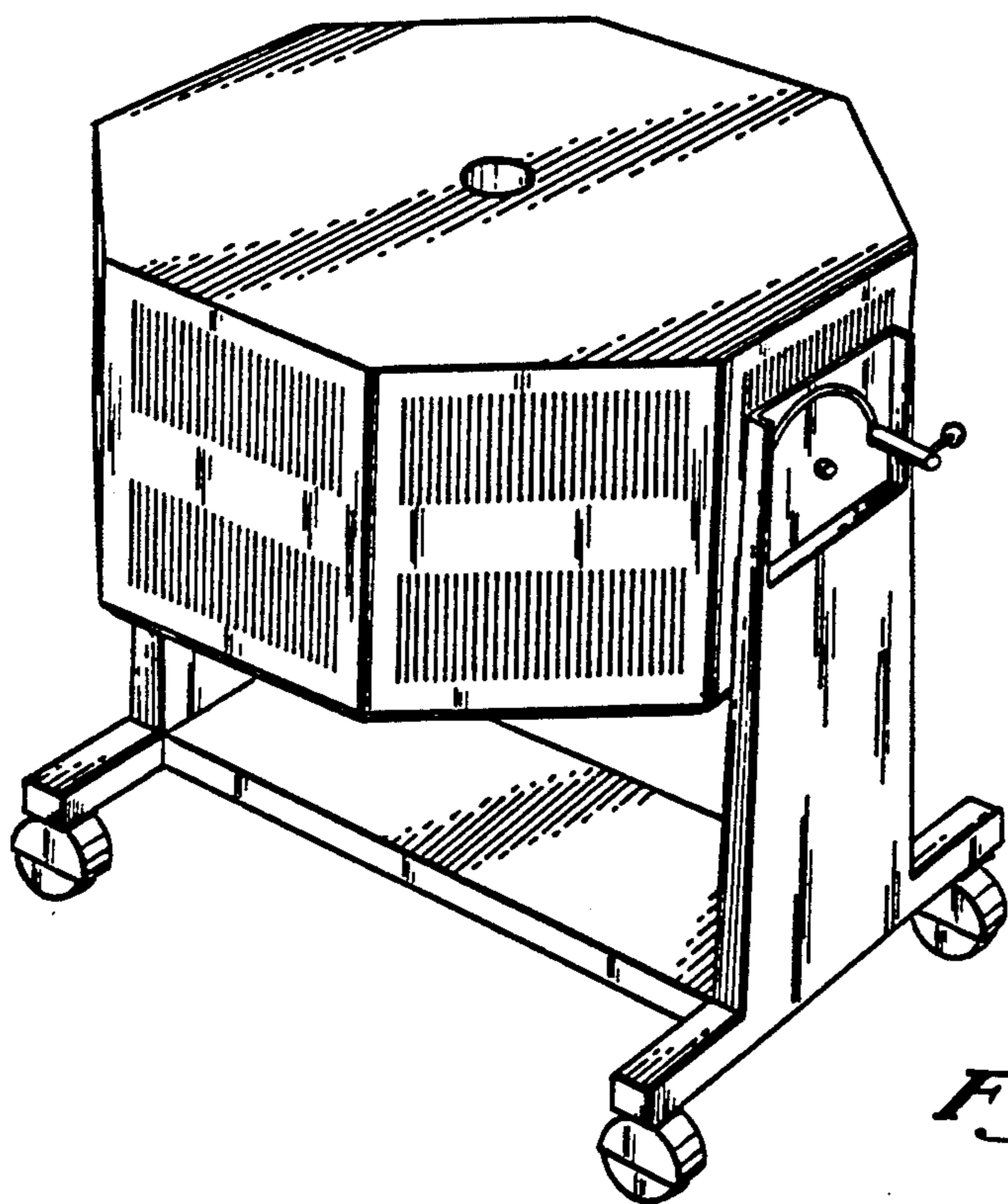
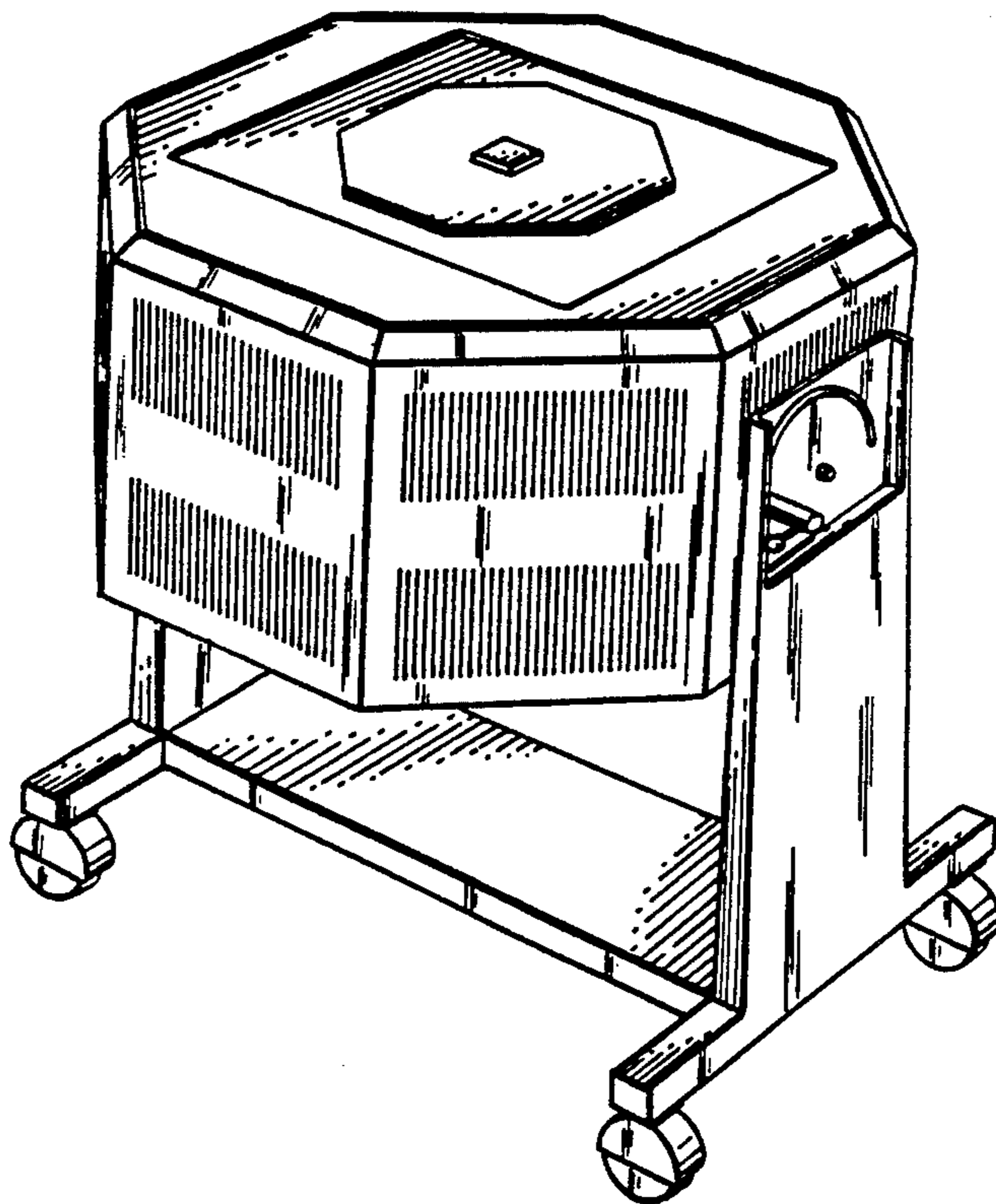


*Fig. 5*



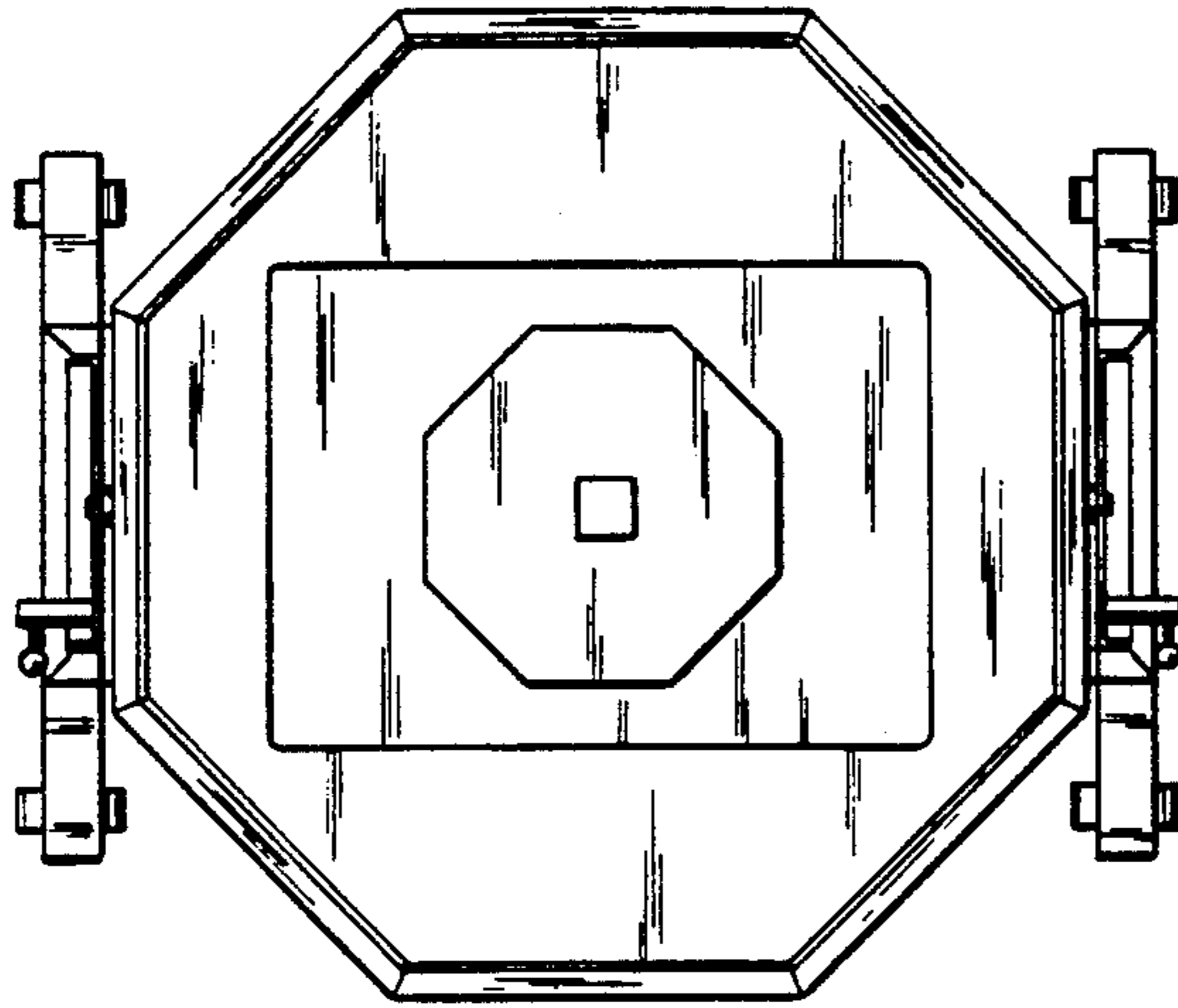
*Fig. 6*

*Fig. 7*

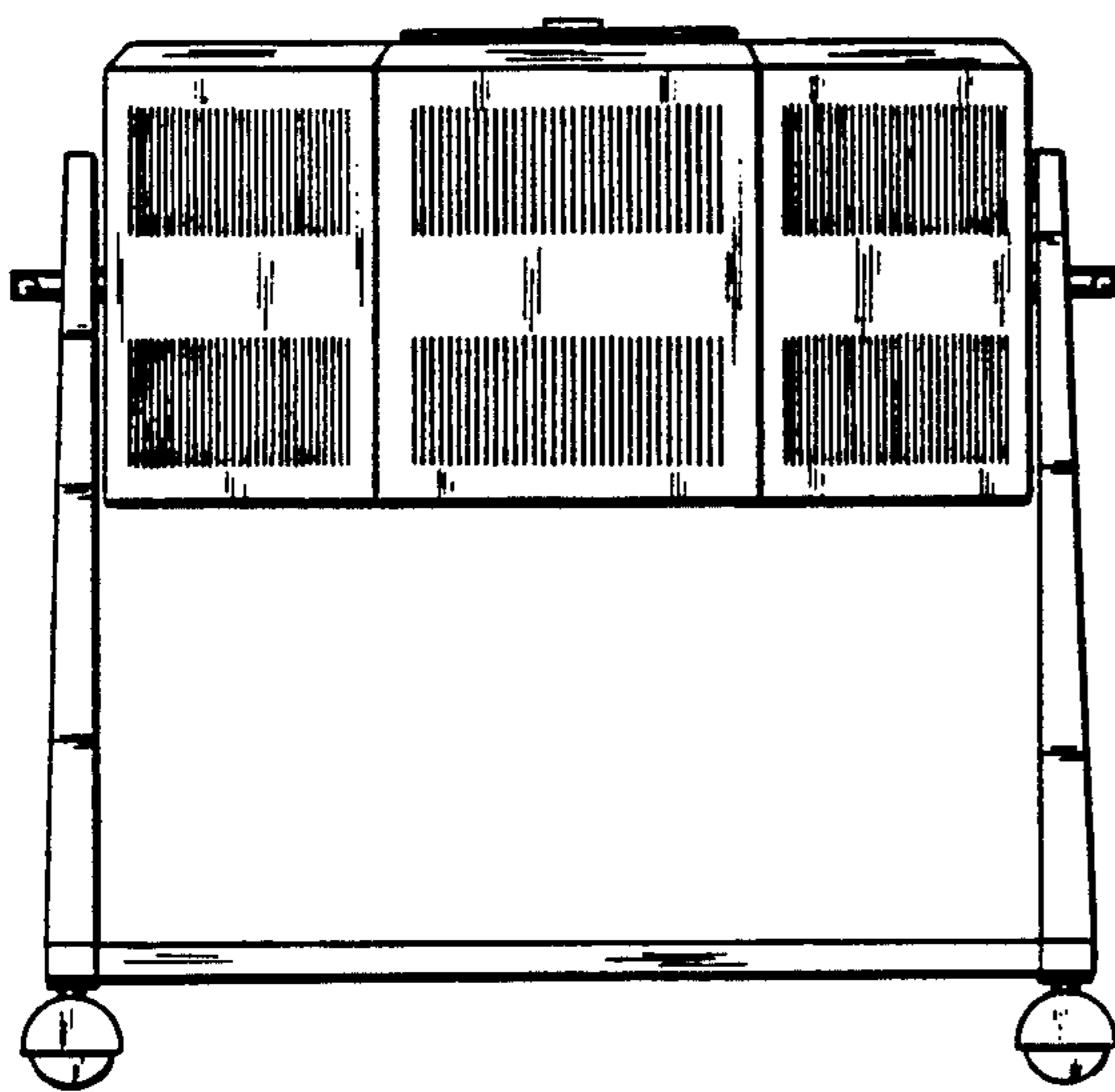
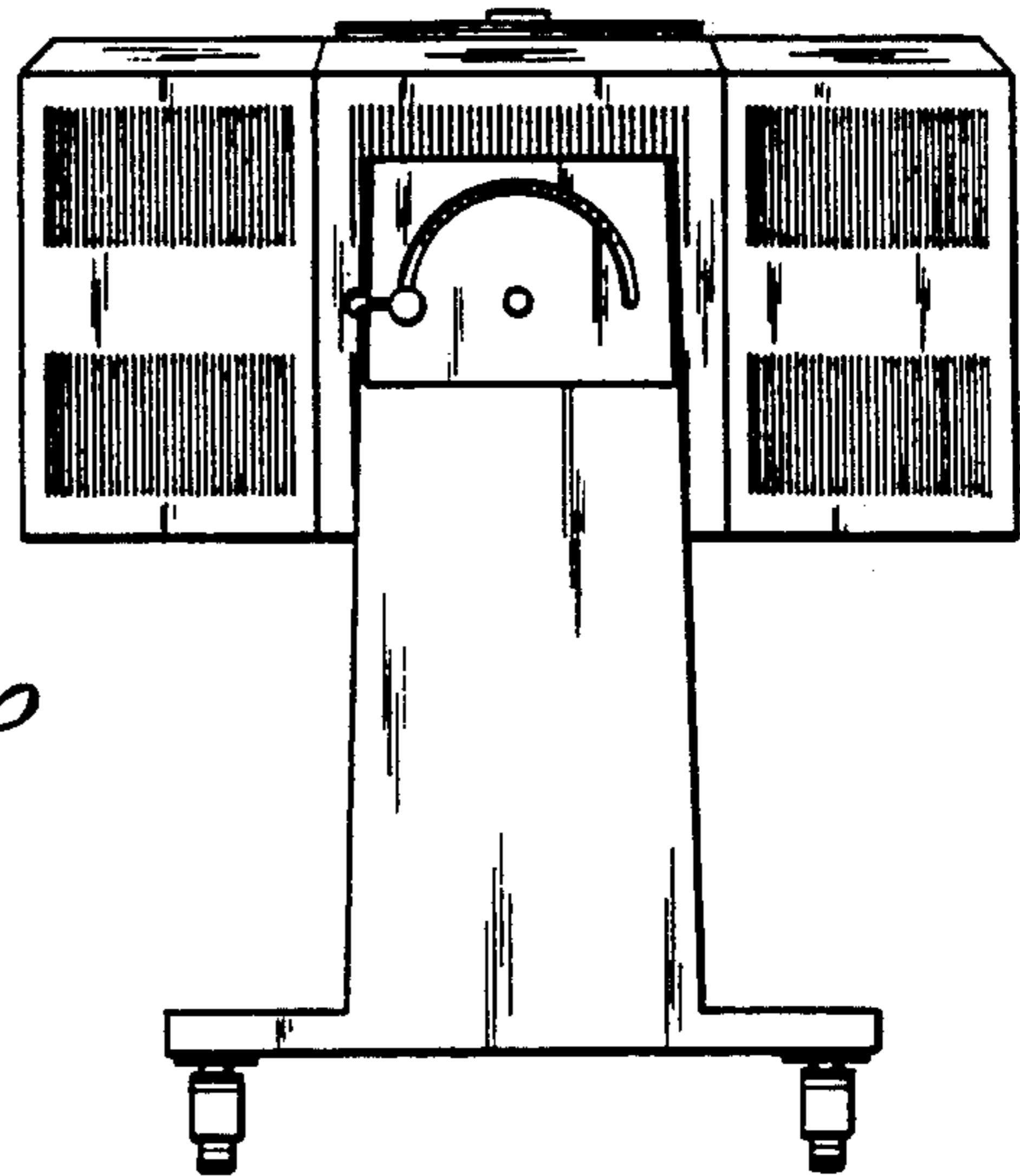


*Fig. 8*

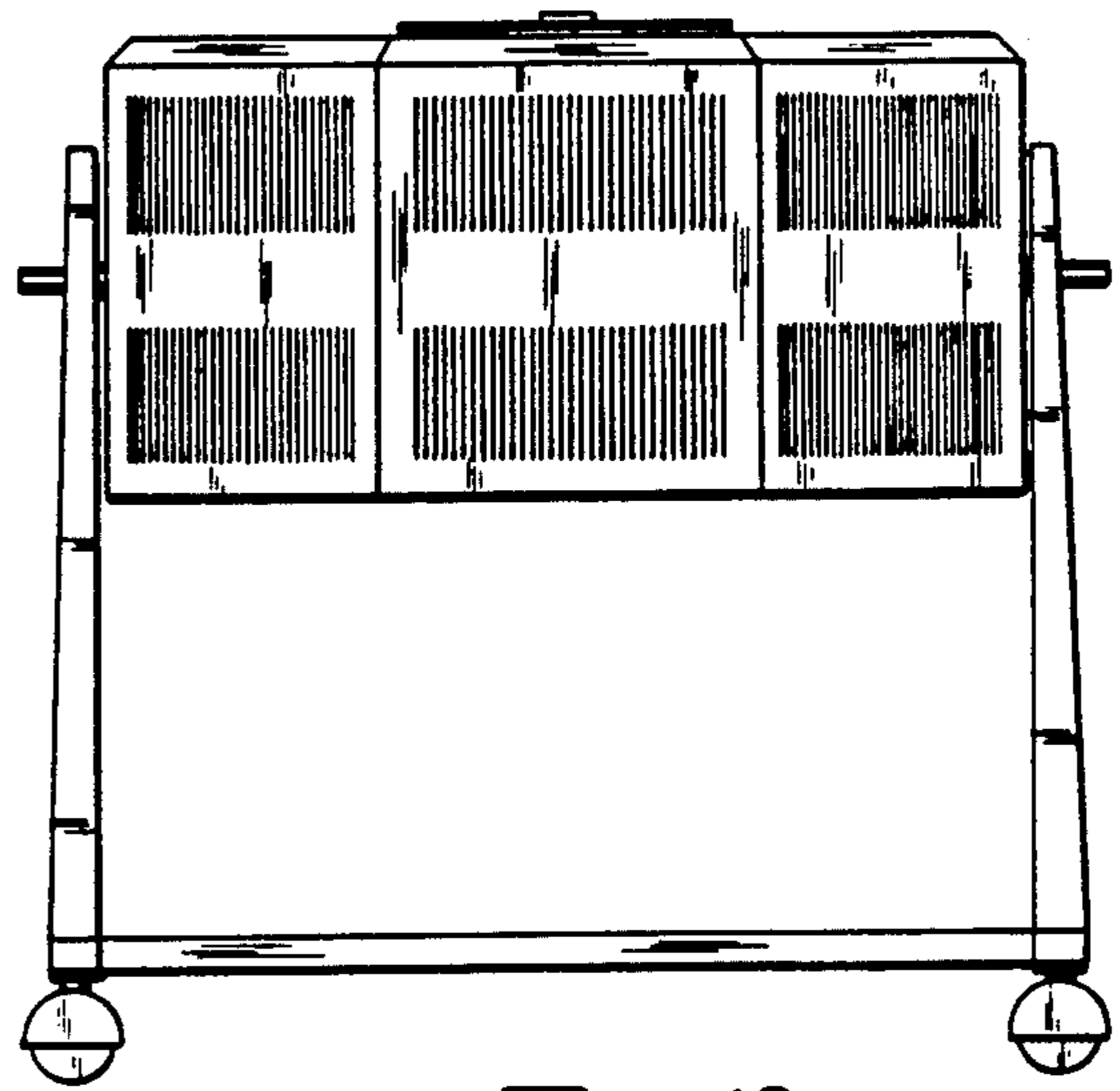
*Fig. 9*



*Fig. 10*

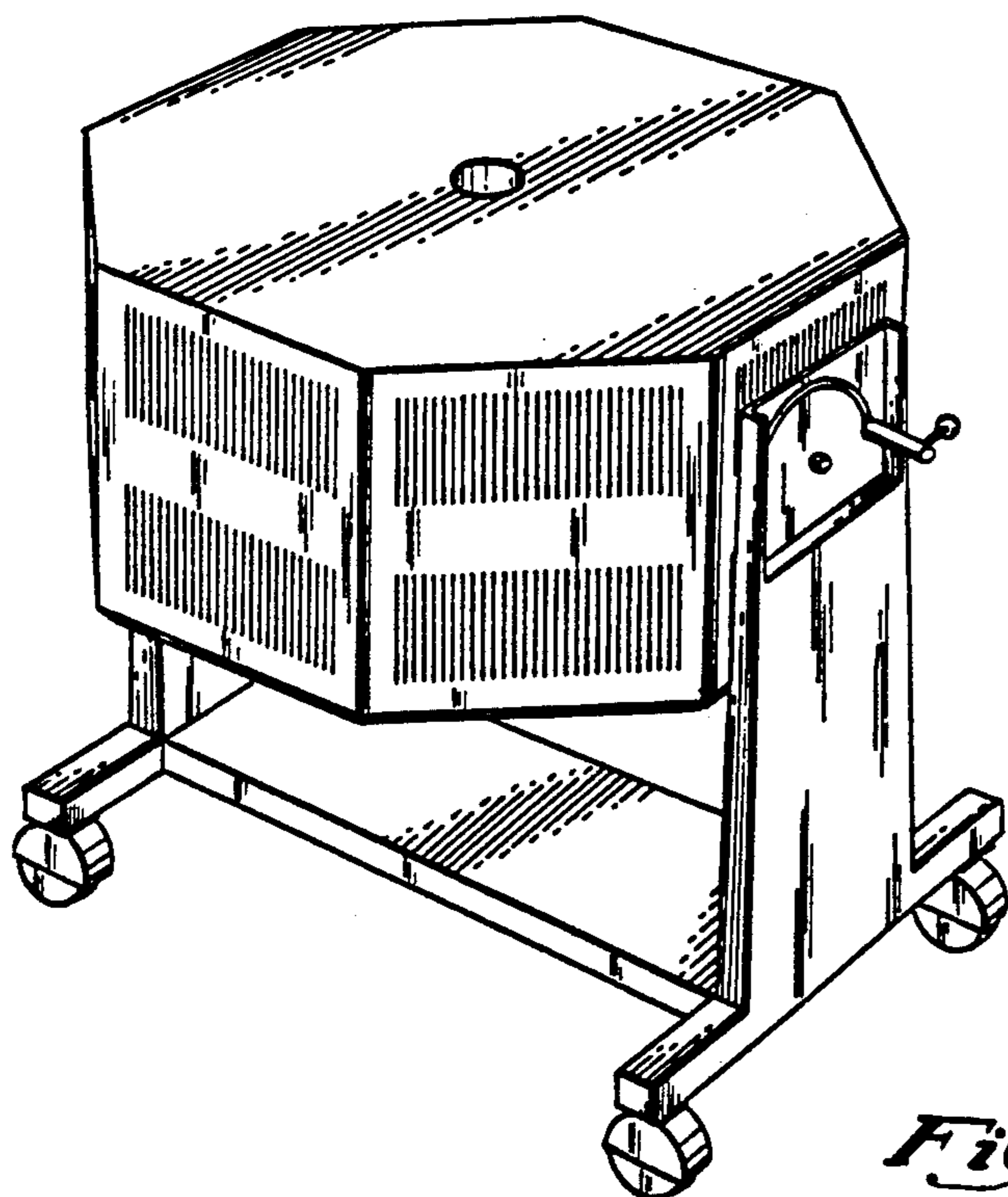
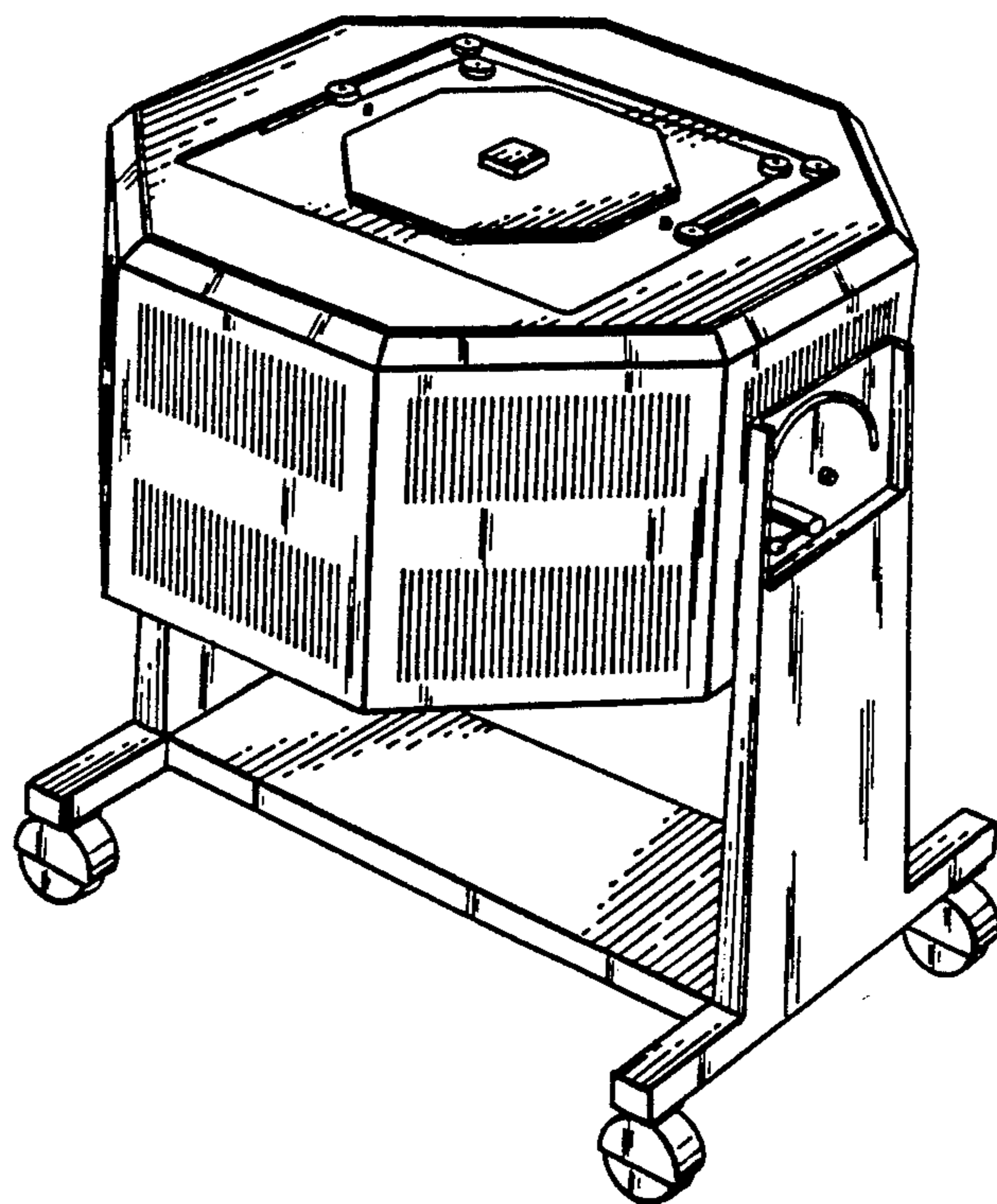


*Fig. 11*



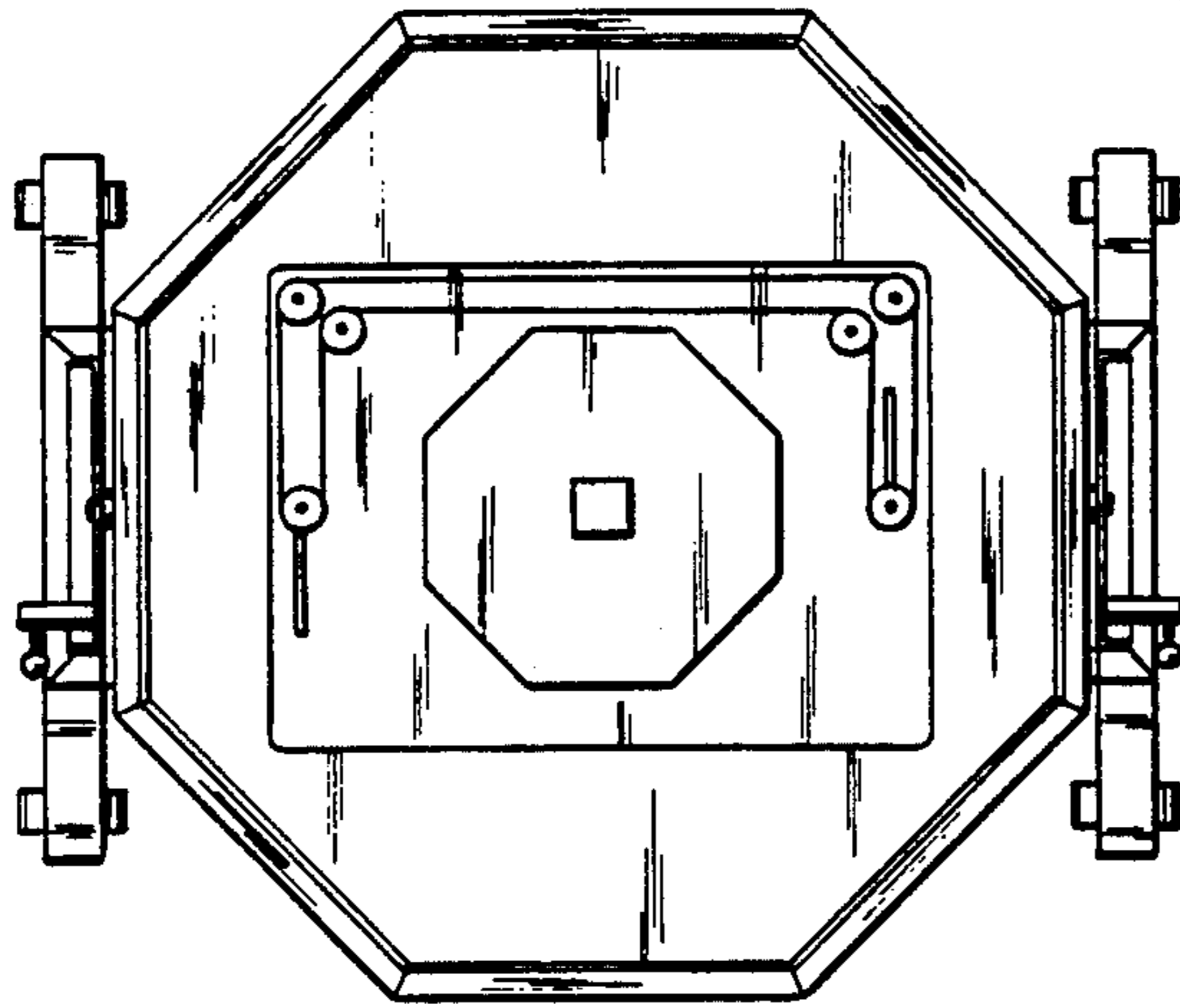
*Fig. 12*

*Fig. 13*

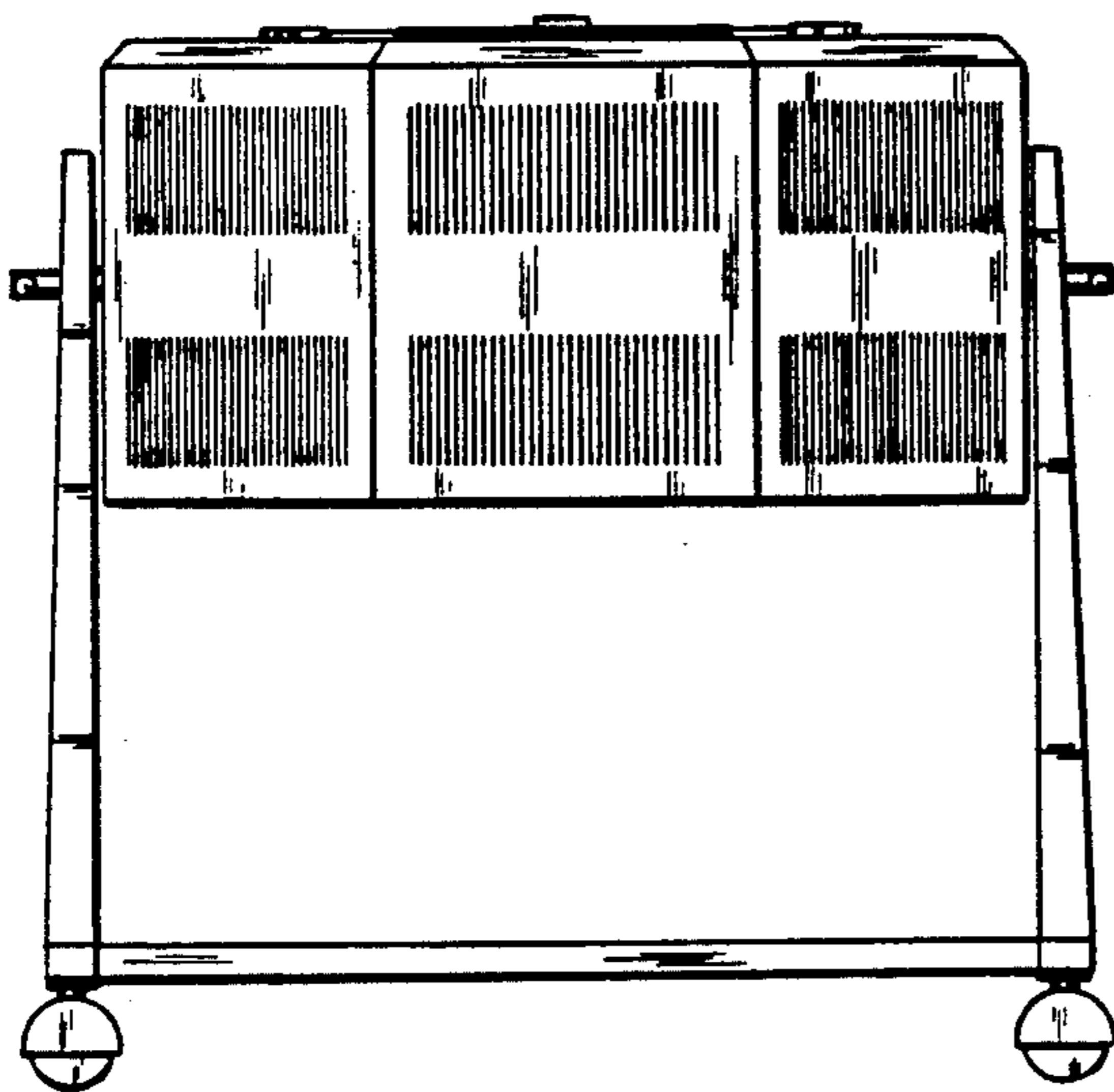
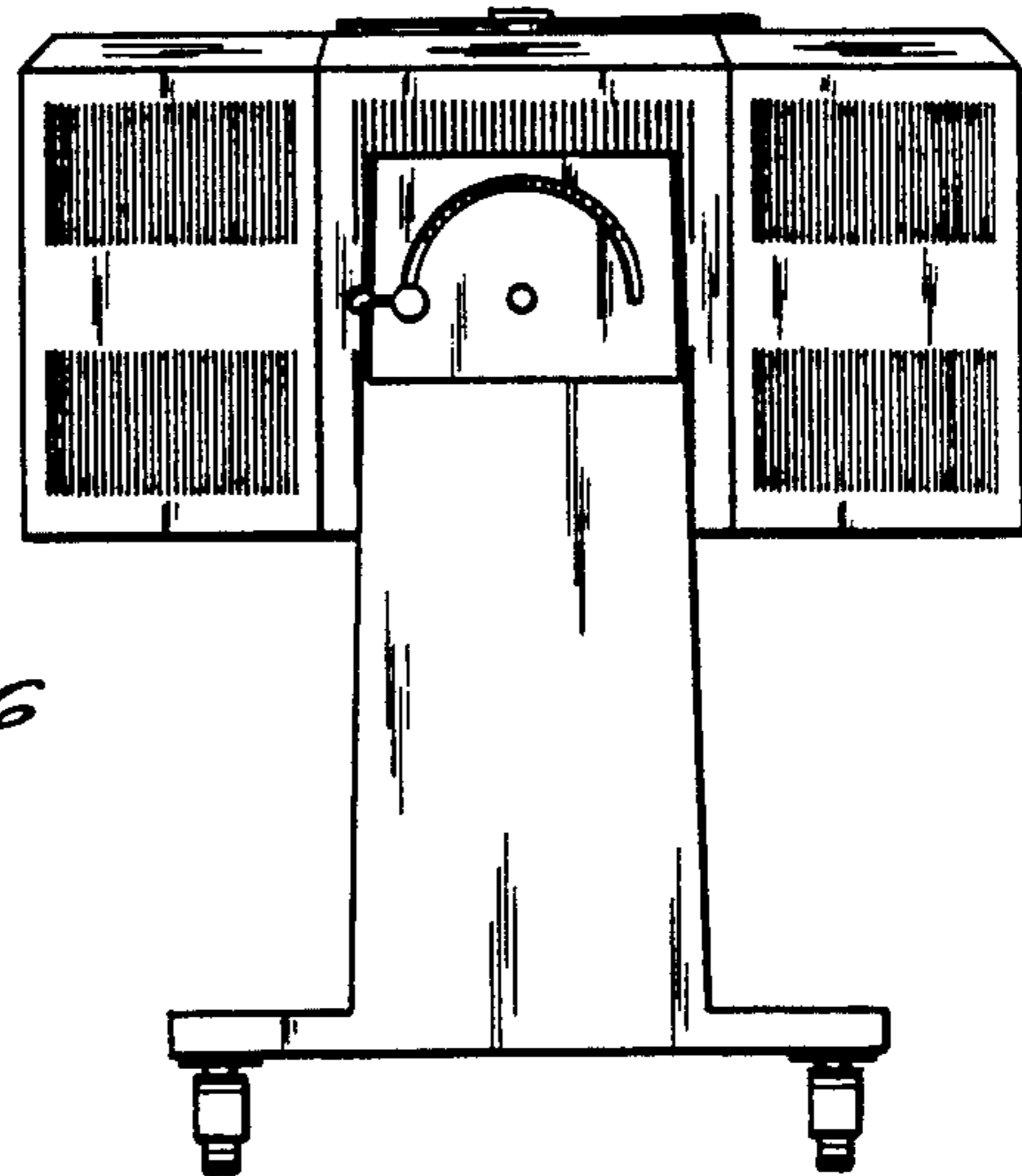


*Fig. 14*

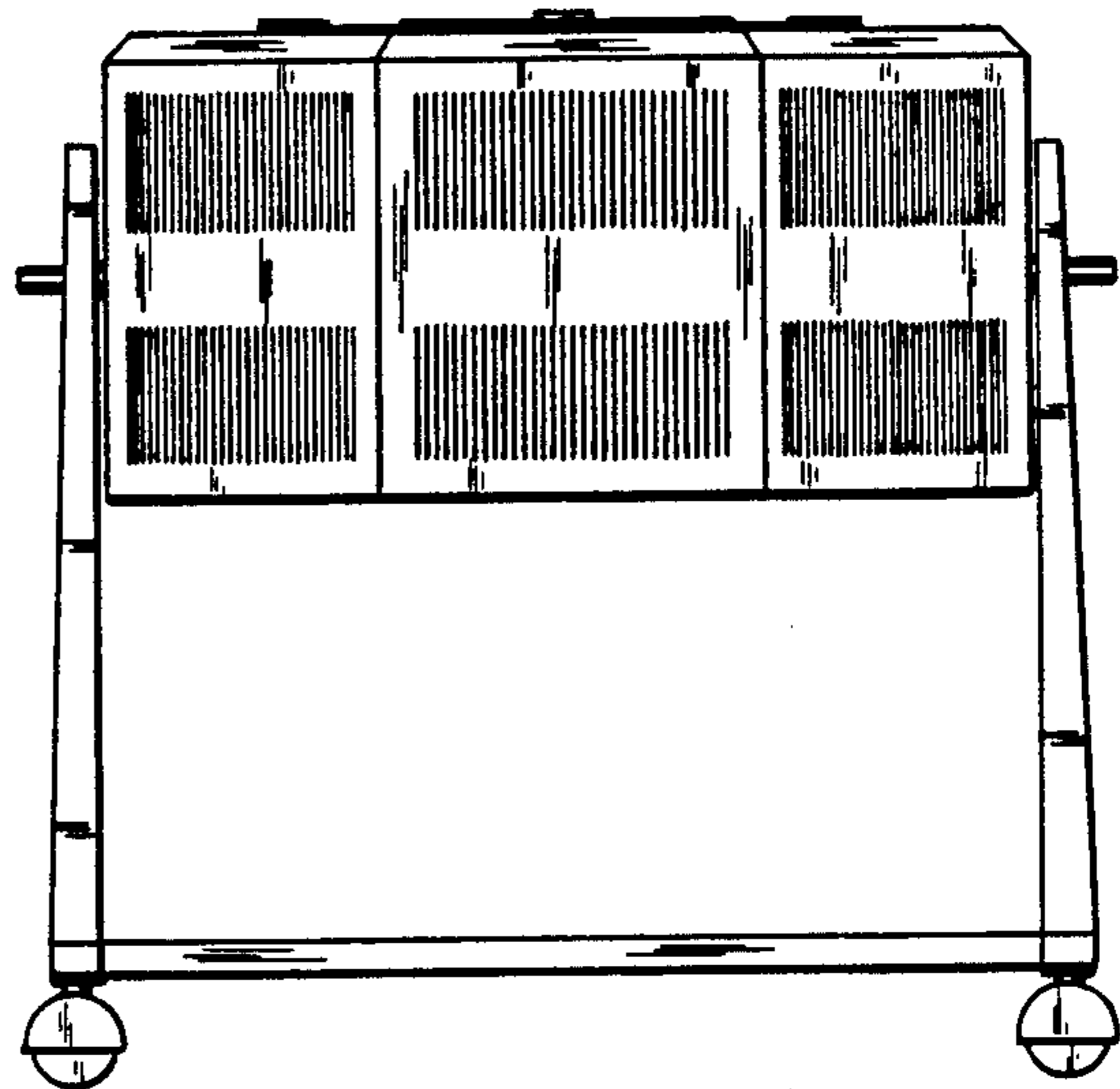
*Fig. 15*



*Fig. 16*



*Fig. 17*



*Fig. 18*

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

**PATENT NO.** : Des. 320,755  
**DATED** : October 15, 1991  
**INVENTOR(S)** : Dahlberg, et al

**It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:**

On the title page, in item [54] and in col. 1, line 2, change "INTERGRATED" to --INTEGRATED--; and

In item [57] Claim, change "a intergrated" to --an integrated--.

In the Description for FIG. 1, change "an intergrated" to --an integrated--.

**Signed and Sealed this  
Thirteenth Day of April, 1993**

*Attest:*

*Attesting Officer*

STEPHEN G. KUNIN

*Acting Commissioner of Patents and Trademarks*